



# LG Fuel Cell Systems Program and Technology Update

DOE 17<sup>th</sup> Annual SOFC Review, 19 July 2016

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# Contracts

## Work performed by LG Fuel Cell Systems under DOE contracts:

- **DE-FE0012077: SECA Coal-Based Systems LGFCS**
- **DE-FE0023337: Improved Reliability of SOFC Systems**
- **DE-FE0026098: Advanced Materials and Manufacturing**

# Outline

- **Performance Improvement**
- **Cost Reduction**
- **Durability**
- **Block Testing**
- **Advanced Materials and Manufacturing**
- **Summary**

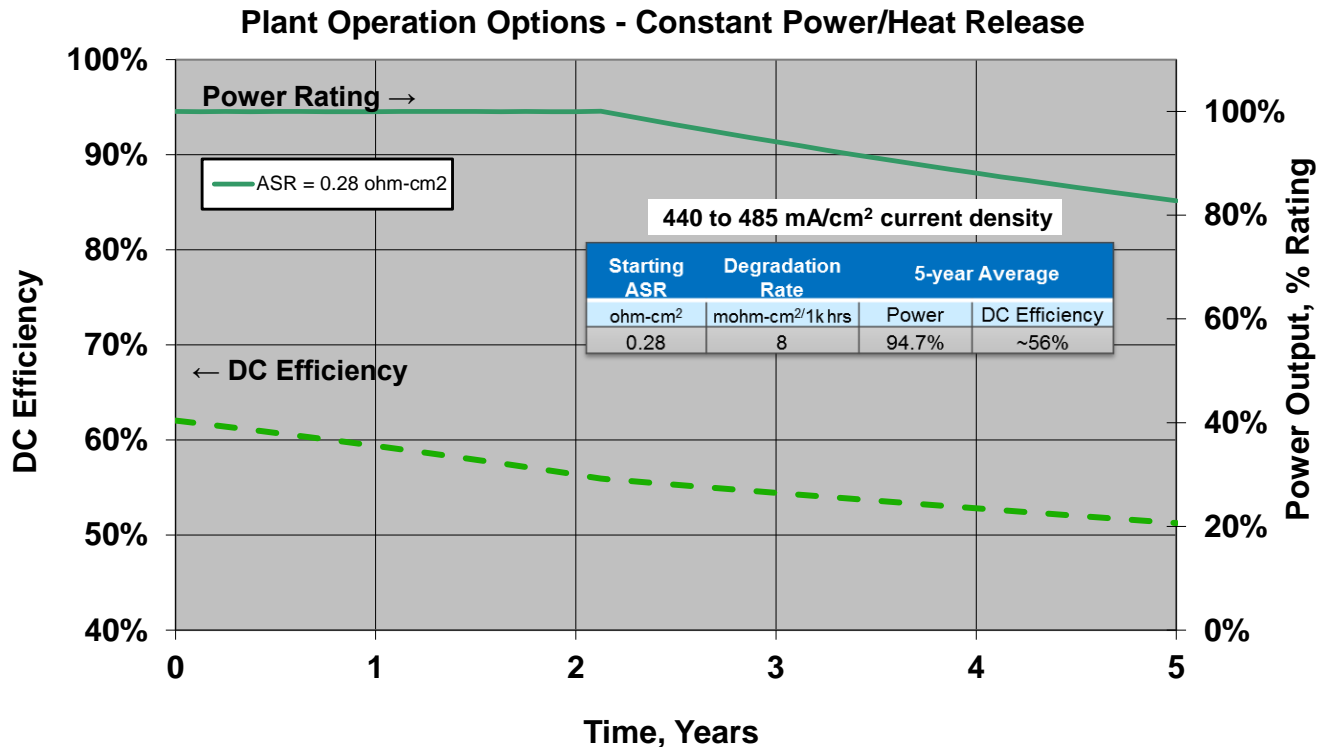
# Outline

- **Performance Improvement**
  - **Fuel cell system operation strategy**
  - **ASR improvement for longer service life and cost reduction**
- **Cost reduction**
- **Durability**
- **Block Testing**
- **Advanced Materials and Manufacturing**
- **LGFCs Program**

# Plant Operation Options Based on Stack Performance

5

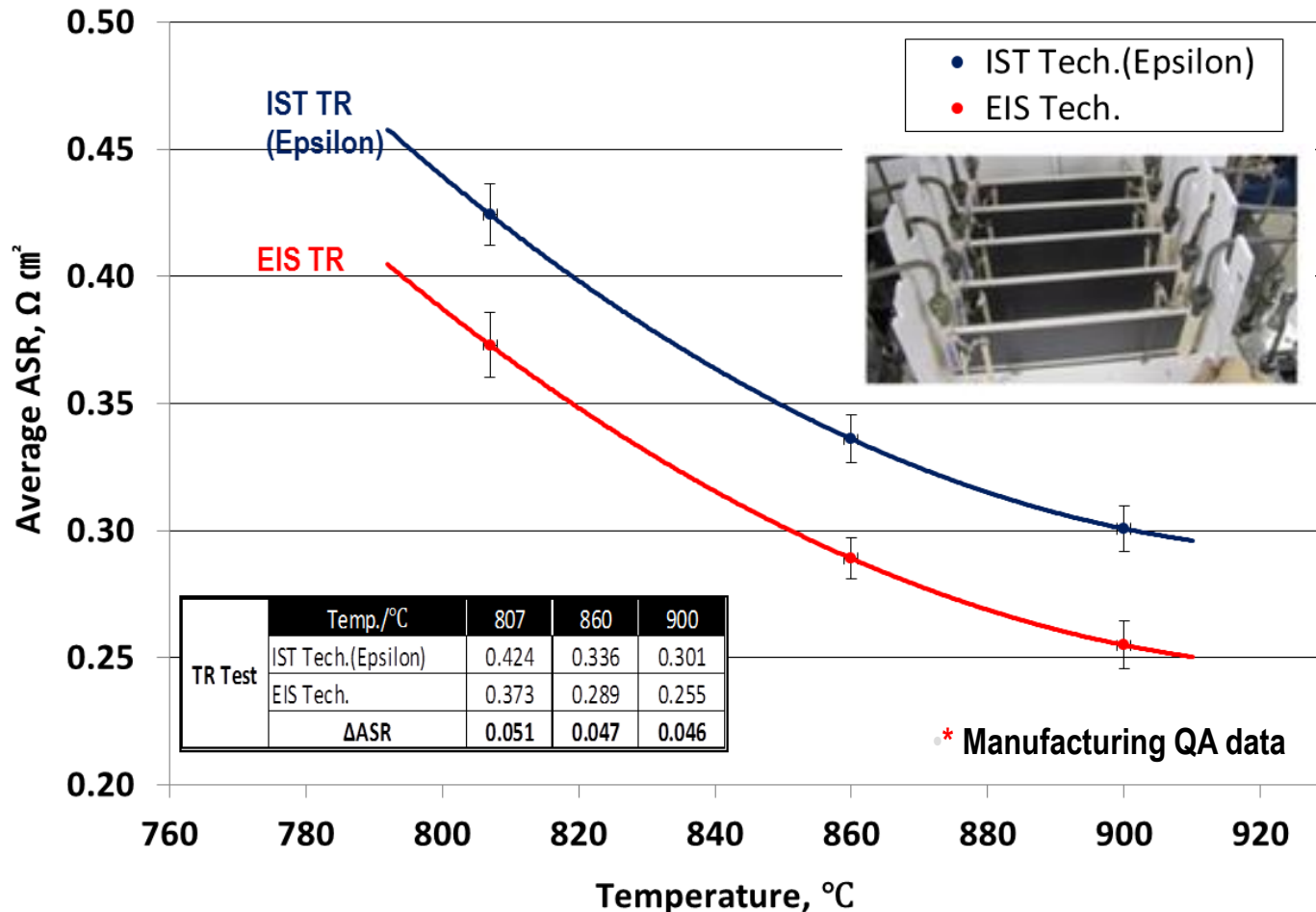
- Initial ASR and ASR degradation rate are key metrics for benchmarking cell technology
- System design must be able to operate over a wide range of ASR (starting to end-of-life) while maintaining specified stack temperature range
- Operation based on current technology developed to date



# ASR Reduction Achievements

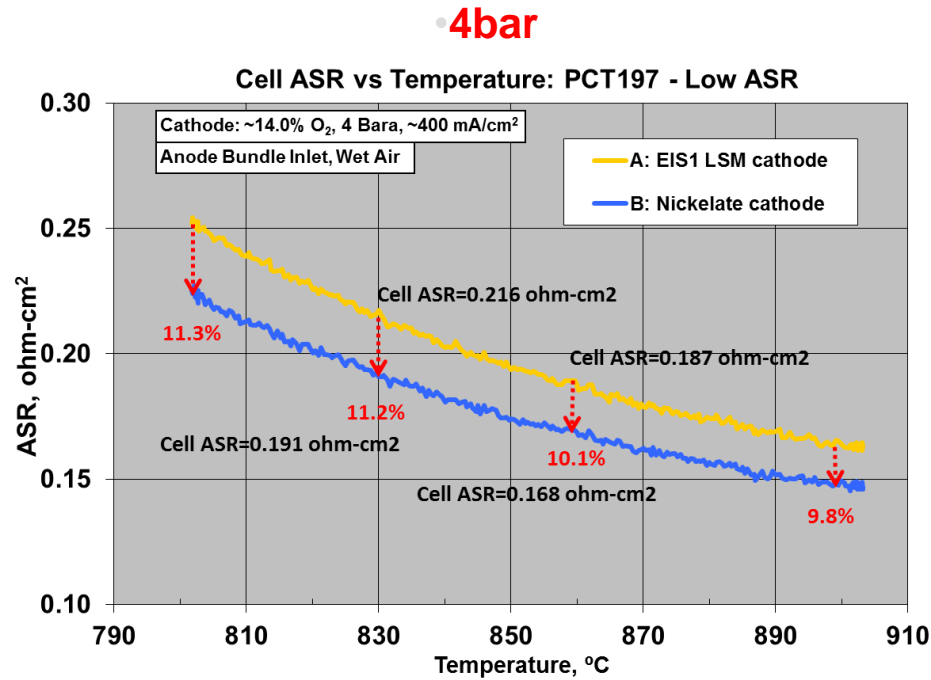
- EIS Tech. provide ASR benefit (0.04~0.05  $\Omega_{cm^2}$ ) compared with IST Tech.

Initial Temperature sweep with Different Tech.



# Additional ASR Reduction Achieved using Nickelate Cathodes

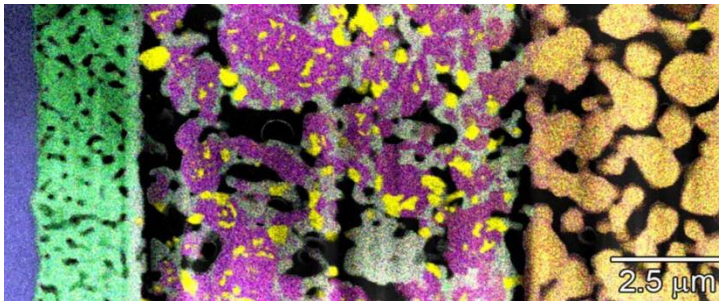
- Candidate nickelate cathodes have  $\sim 0.02$  Ohm  $\text{cm}^2$  lower cell ASR at 860C, 4bar



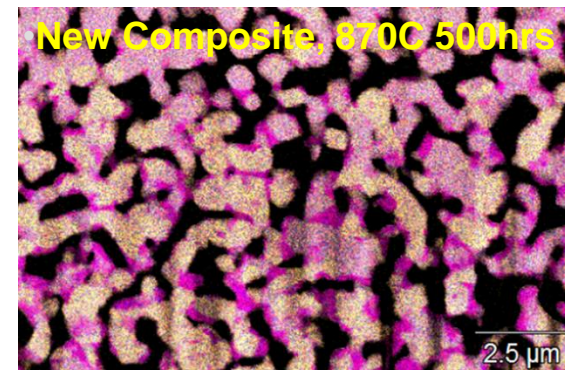
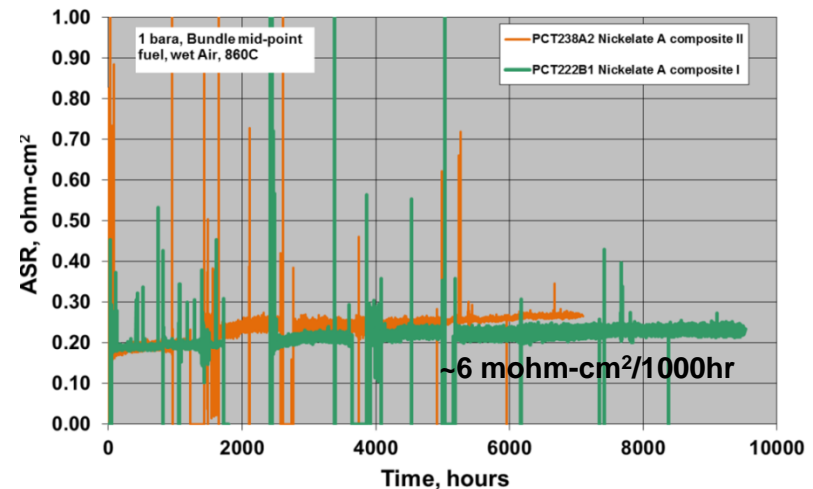
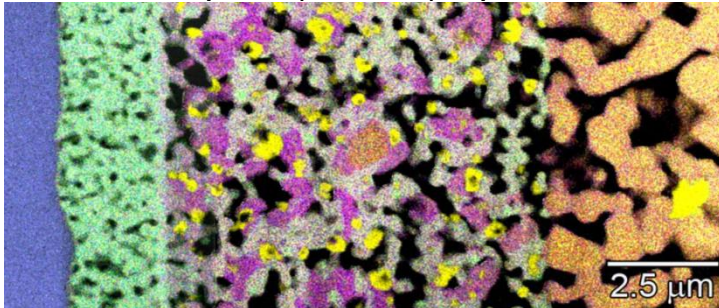
# Current Status for Nickelates

- Difficult to achieve complete phase stability
- But, still promising durability even with multiple phases present
- Recent further improvements in degree of phase instability

Nickelate composite II (PCT238 A2) Elapsed time : 7200hr



Nickelate composite I (PCT222 B1) Elapsed time : 9500hr



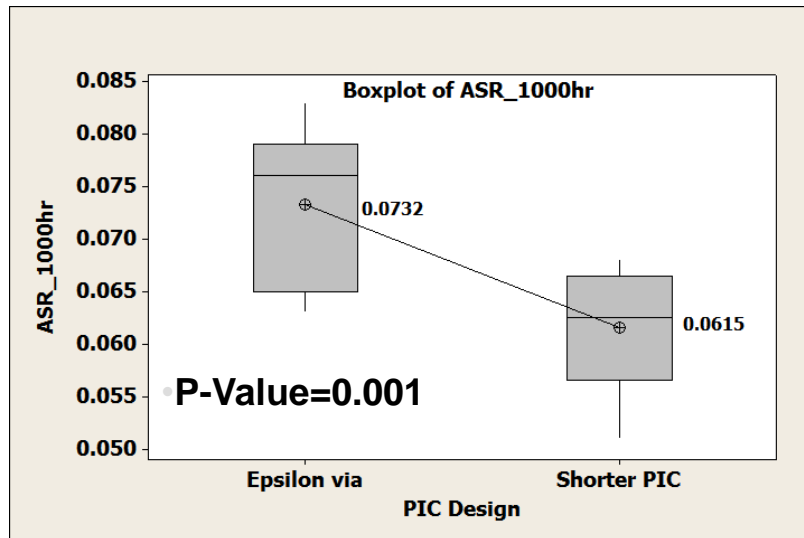
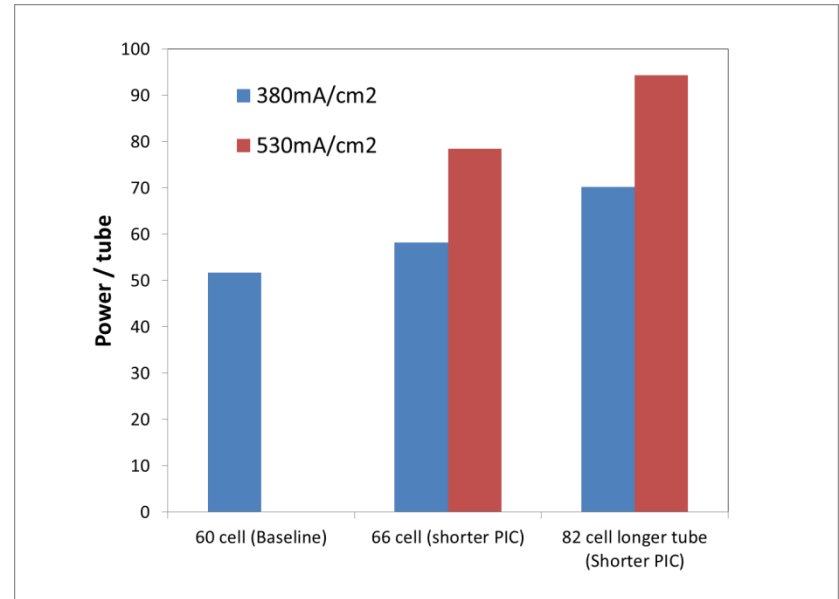


# Outline

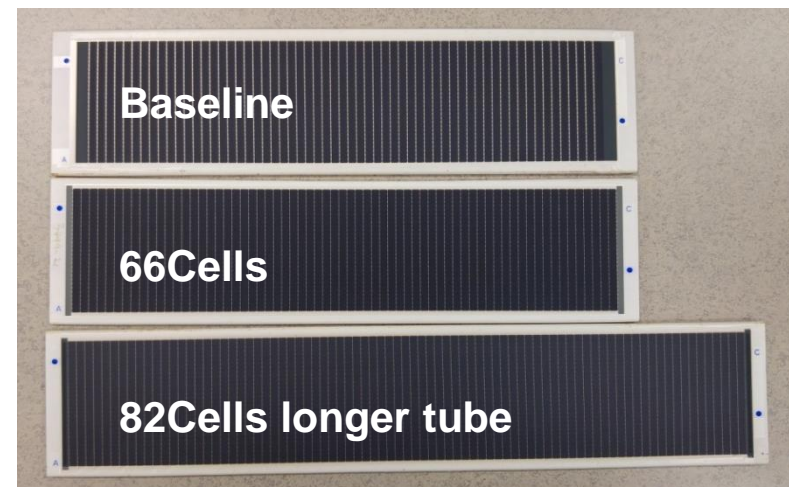
- Performance improvement
- **Cost reduction**
  - **Cell and stack design changes**
  - **Current density**
  - **System simplification for cost reduction**
- Durability
- Block Testing
- Advanced Materials and Manufacturing
- LGFCS Program

# Cell & Tube Design Options for ASR Reduction & Power Increase

- Smaller PIC dimension has lower ASR contribution
- Power increased using longer tube (~100W/tube)



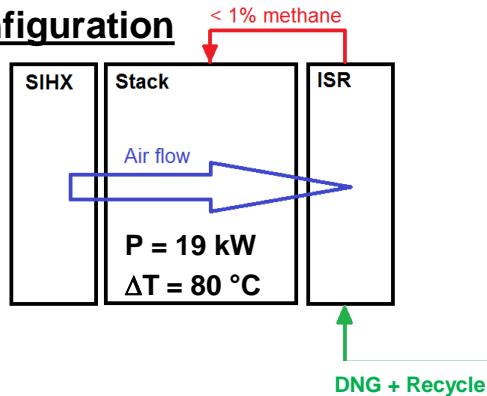
PIC ASR reduction: 0.012 Ohm cm2 (PCT)



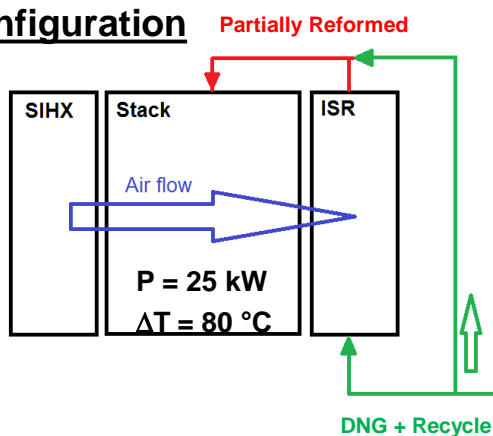
# In-Block Reforming Enables Higher Power Density 11

- In Block Reforming reduces stack DT to allow higher power density for the same air flow
- Single tube mapping tests showed no evidence of performance loss with various levels of IBR
- Low ASR enables higher current density while maintaining efficiency

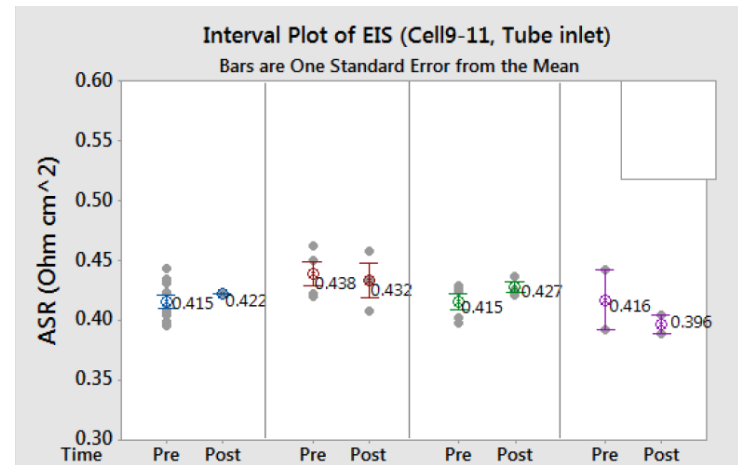
## IST configuration



## IBR configuration

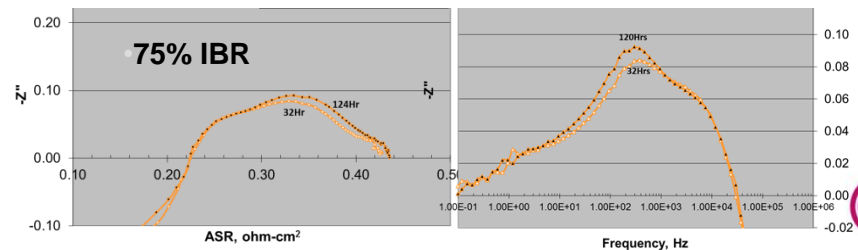


## Cell performance



Increasing % IBR  $\longrightarrow$

## No change in anode peak



# Anode Protection System Simplification for Cost Reduction

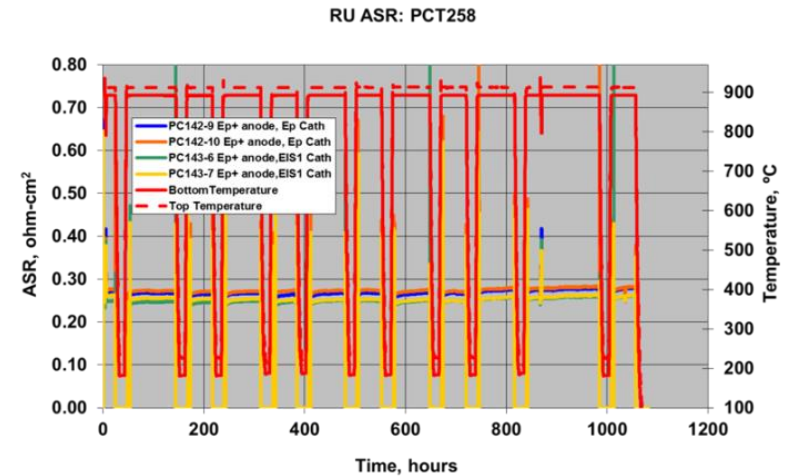
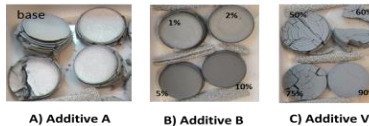
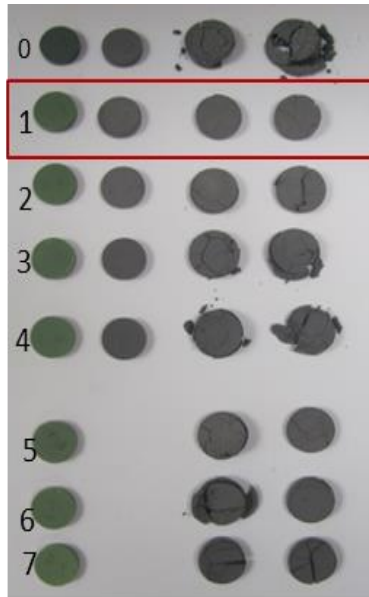
- Operational scheme results in anode redox
- A minimal number of redox cycles required for product
- cost reduction by 75% from early design of Anode Protection Unit

• Early system designs utilized a separate subsystem for system scale APG generation

## Catalytic Anode Protection Gas System



- Pellet Redox
- Exposure to air for 2 hrs at 900C
- 5 cycles

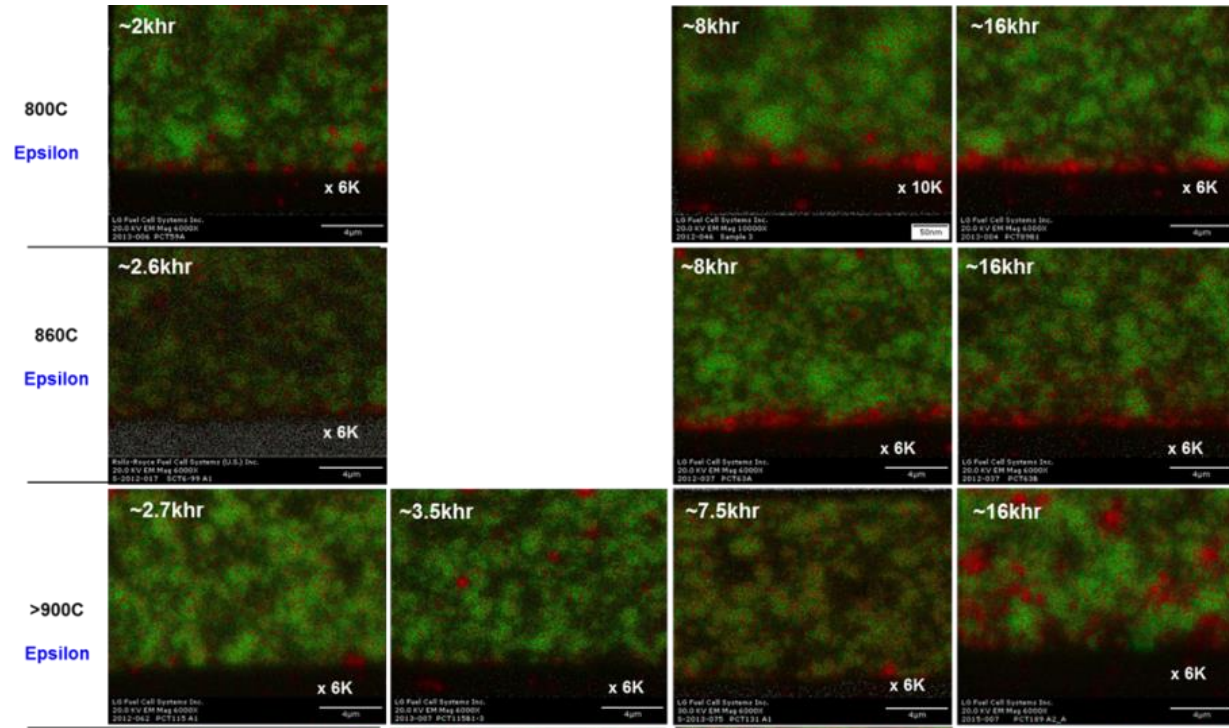


# Outline

- Performance improvement
- Cost reduction
- **Durability**
  - Cathode
  - Anode
  - PIC
  - **Degradation rate**
- Block Testing
- Advanced Materials and Manufacturing
- LGFCS Program

# MnOx Accumulation, Redistribution Status of Understanding, Solutions

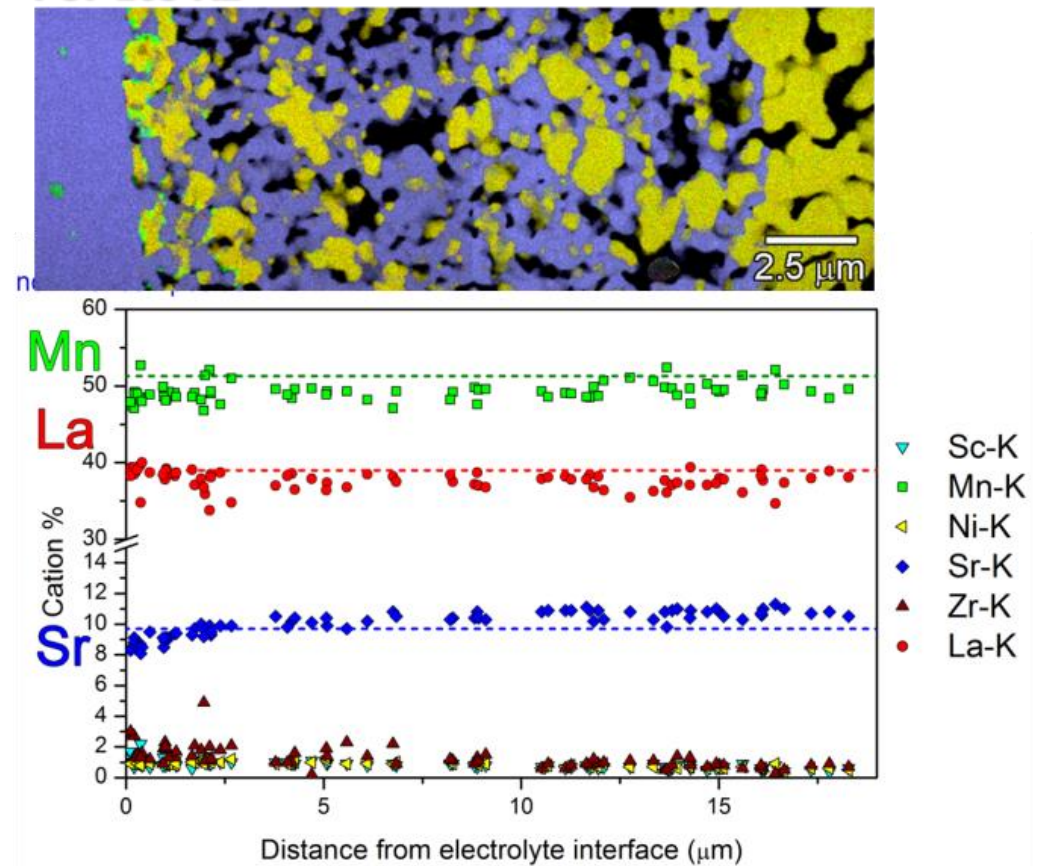
- **Mn enrichment** greater at low temperature





# MnOx Accumulation, Redistribution Status of Understanding, Solutions

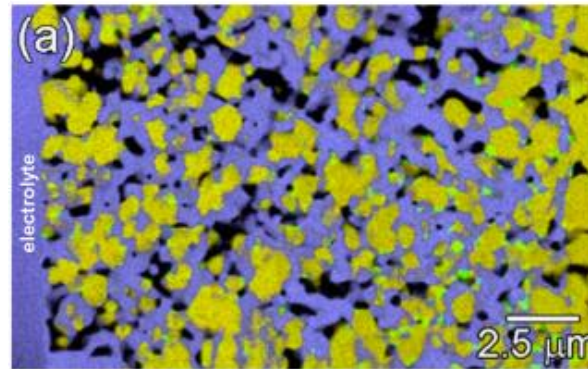
- Mn enrichment greater at low temperature
- MnOx source appears to be from throughout the cathode and CCC layers. No significant localized LSM stoichiometry change
  - Even 5% A-site deficient CCC has free-MnOx as-fabricated.



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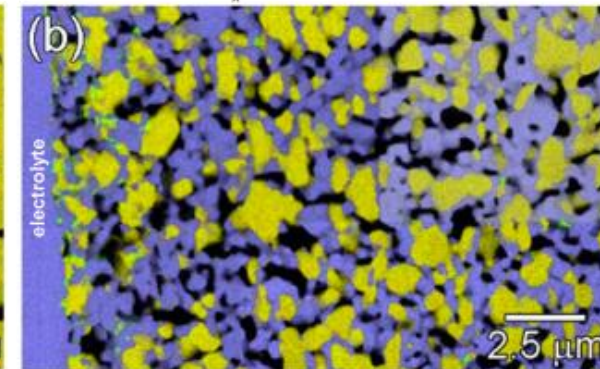
- Mn enrichment greater at low temperature
- MnOx source appears to be from throughout the cathode and CCC layers. No significant localized LSM stoichiometry change
  - Even 5% A-site deficient CCC has free-MnOx as-fabricated.
- Localized at interface (driving force?)
  - Overpotential and/or pO<sub>2</sub>

Reference cell w/o current load  
- MnO<sub>x</sub> at cathode/CCC interface



Active cell with current load

- MnO<sub>x</sub> at electrolyte
- MnO<sub>x</sub> elimination from bulk cathode



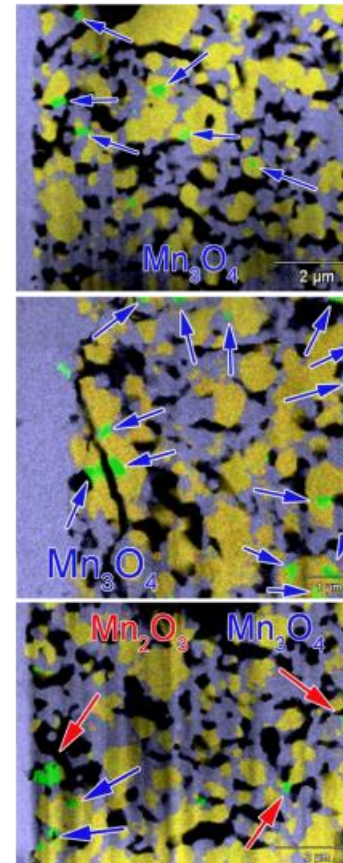
- Tested ~5000 hrs at 925°C and 4 bar

■ Mn  
■ LSM



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  - Even 5% A-site deficient CCC has free-MnOx as-fabricated.
- Localized at interface (driving force?)
  - Overpotential and/or pO<sub>2</sub>
- Mn valence along interface
  - Using EELS



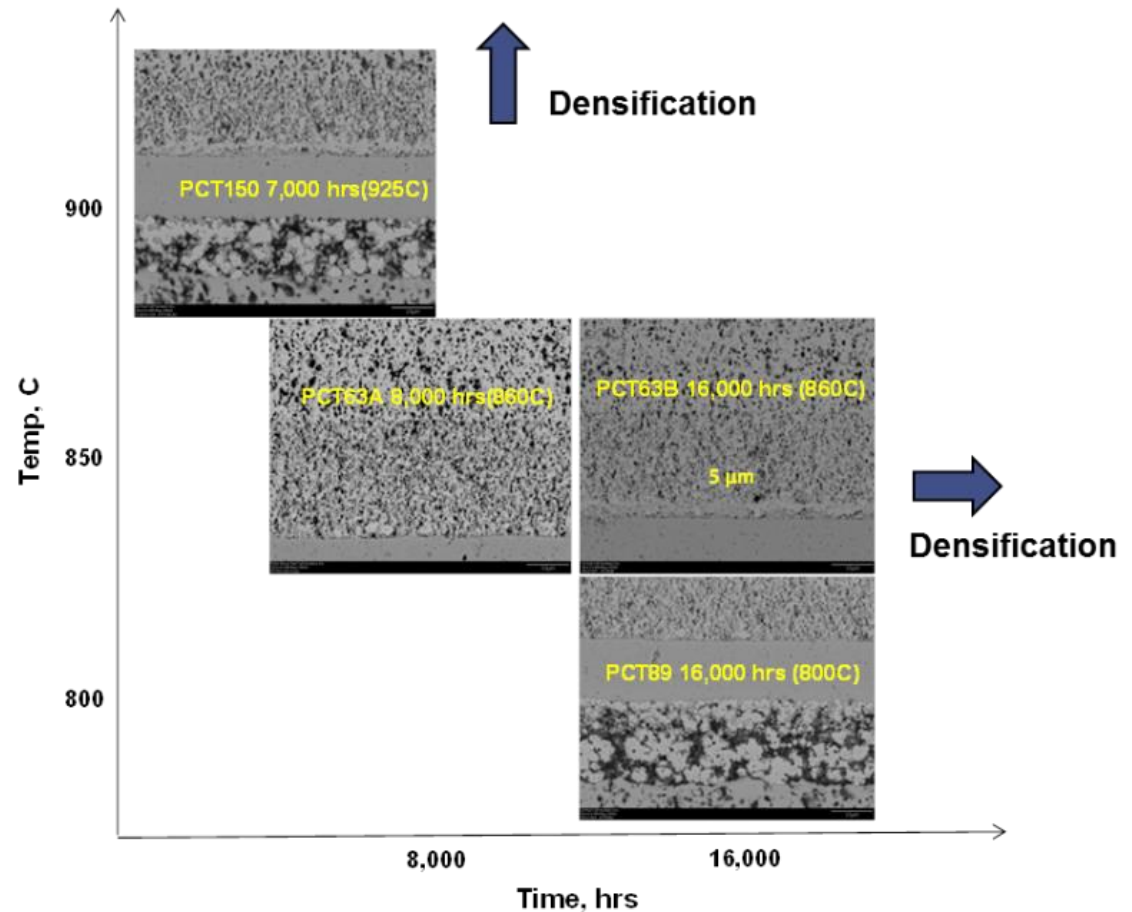
As fired

900C

800

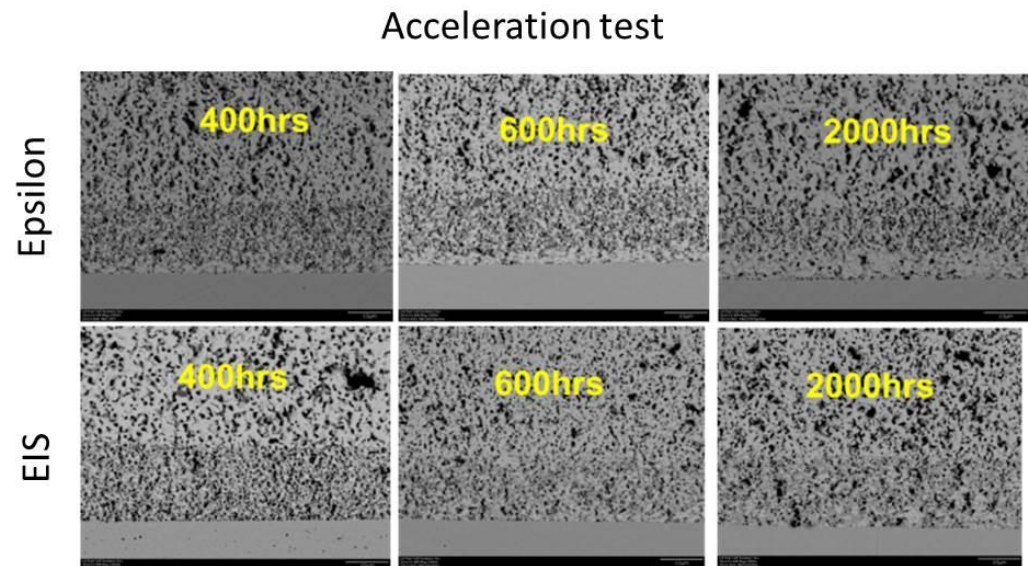
# Cathode Densification – Status of Understanding, Solutions

- Densification greater at high temperature



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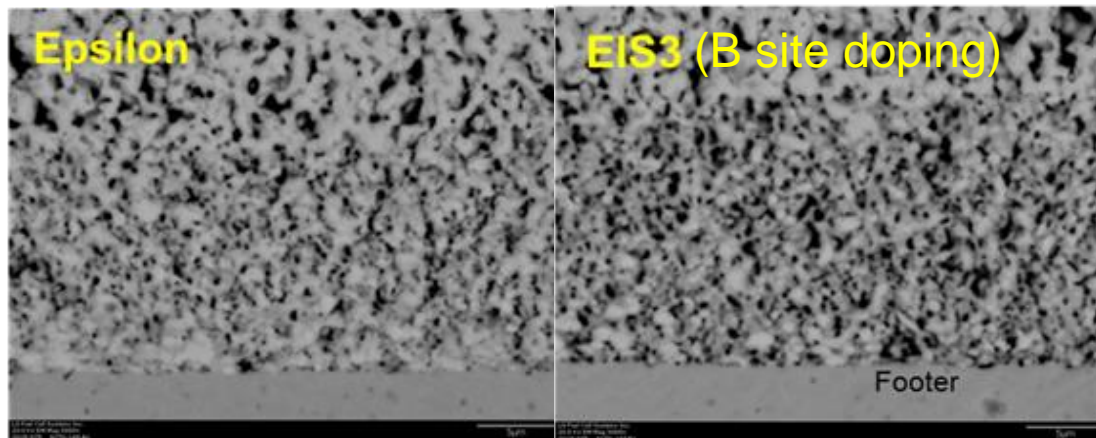
- Densification greater at high temperature
- Densification is greatest under localized low  $pO_2$  if kinetics are high
  - Pressurized SOFC benefit higher  $pO_2$
- Degree of A-site deficiency influences densification



# Cathode Densification – Status of Understanding, Solutions

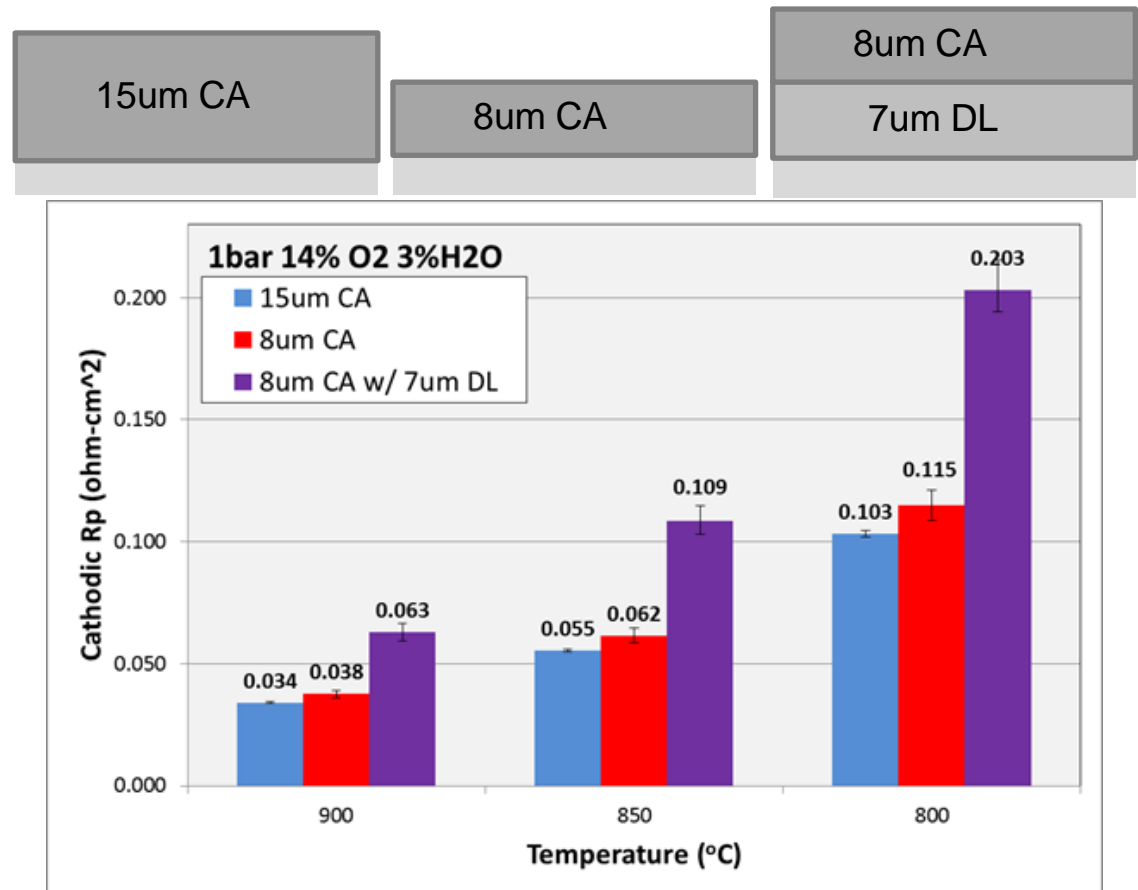
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- Degree of A-site deficiency influences densification
- **B-site dopant selection can reduce densification**

Acceleration test 1000hr



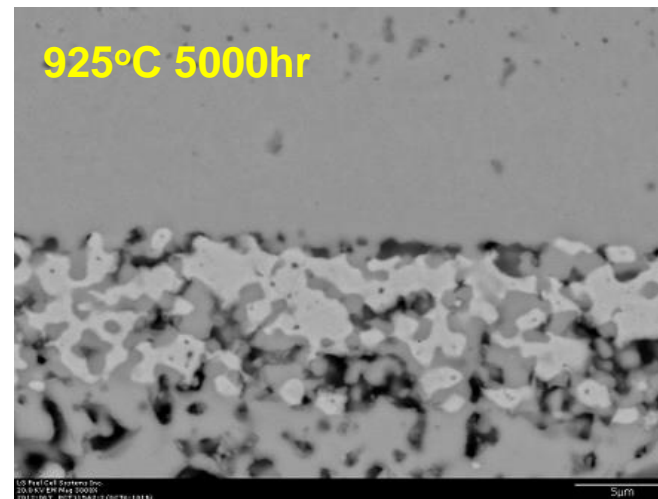
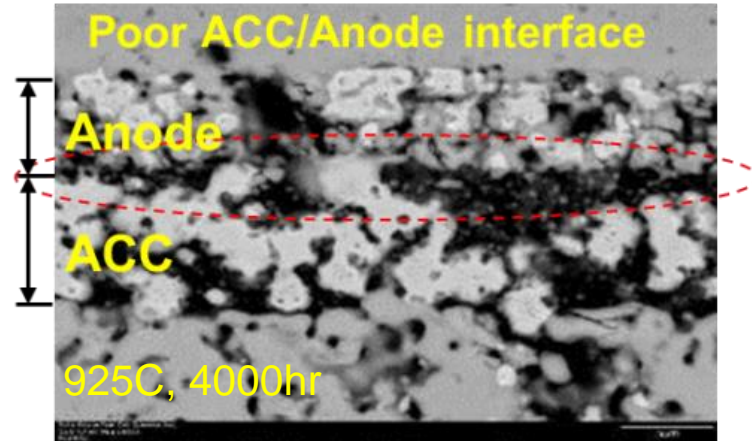
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  - Pressurized SOFC benefit higher  $pO_2$
- Degree of A-site deficiency influences densification
- B-site dopant selection can reduce densification
- Densification increases  $R_p$



# Anode Degradation– Status of Understanding, Solutions

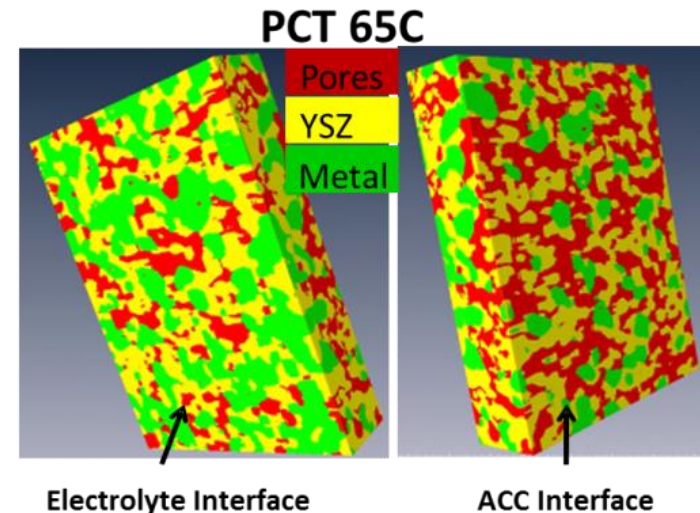
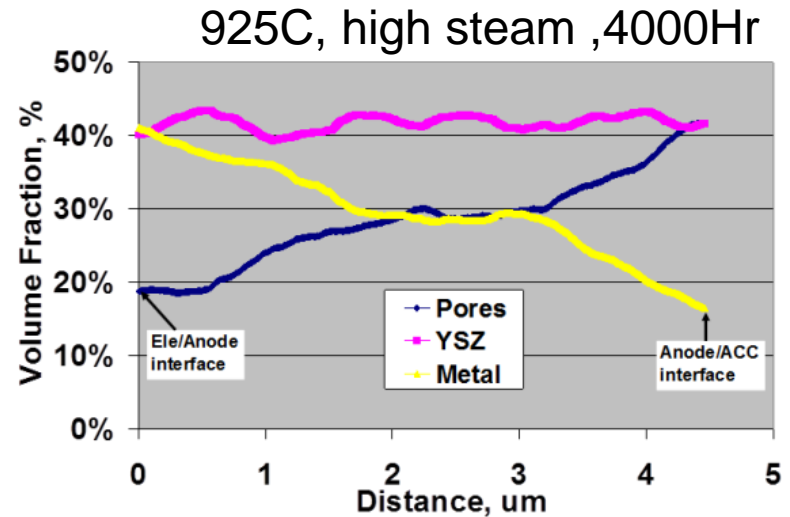
- Bilayer anode+ACC versus single layer
  - Avoidance of interfaces resistance





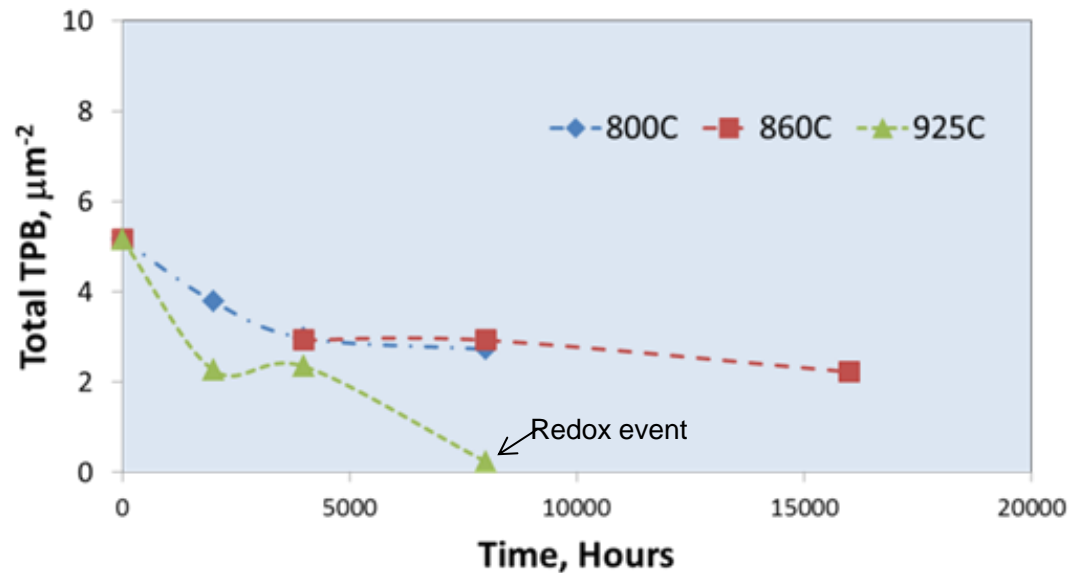
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- Ni accumulation along interface at high temp and higher  $U_f$



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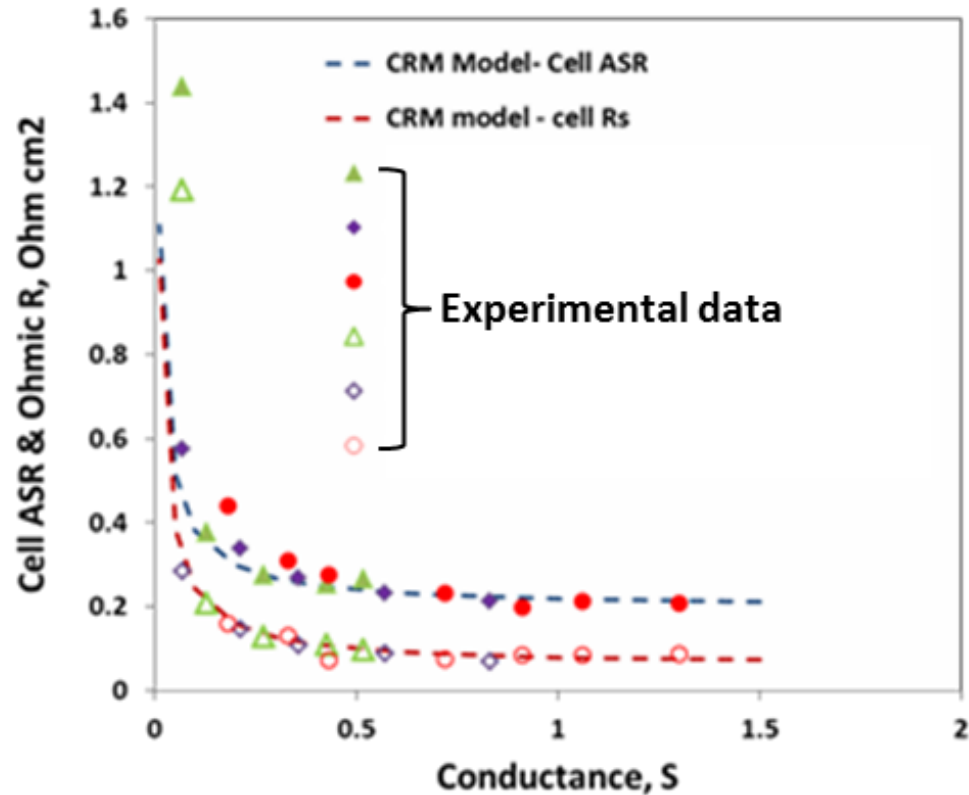
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- Ni accumulation along interface at high temp and higher  $U_f$
- Loss of TPB





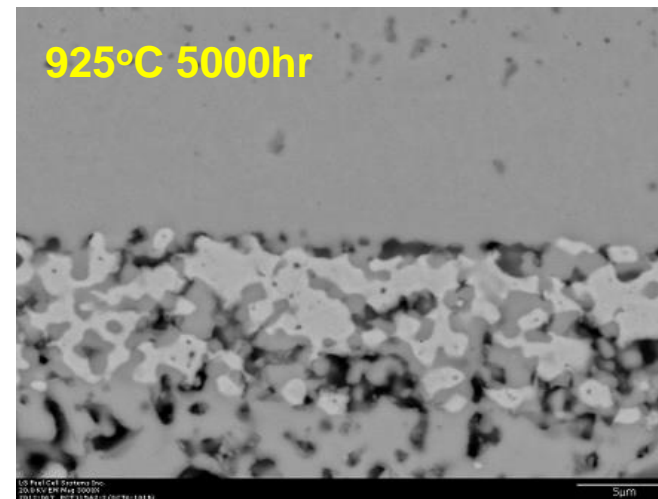
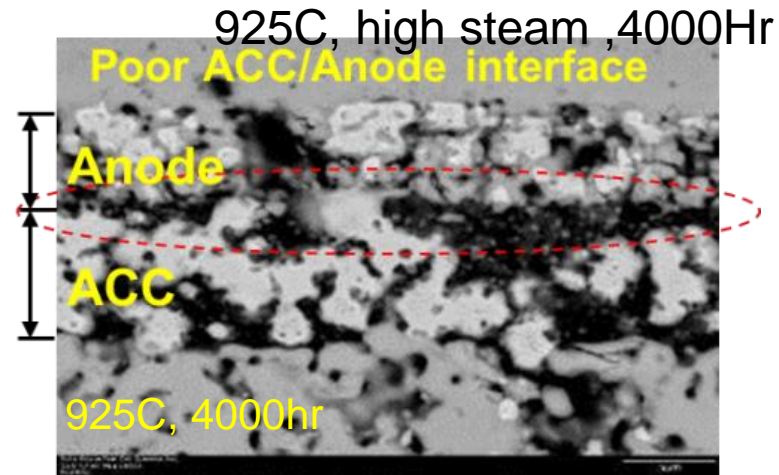
# Anode Degradation– Status of Understanding, Solutions

- Bilayer anode+ACC versus single layer
  - Avoidance of interfaces resistance
- Ni accumulation along interface at high temp and higher  $U_f$
- Loss of TPB
- **Anode-side conductivity retention important for durability**



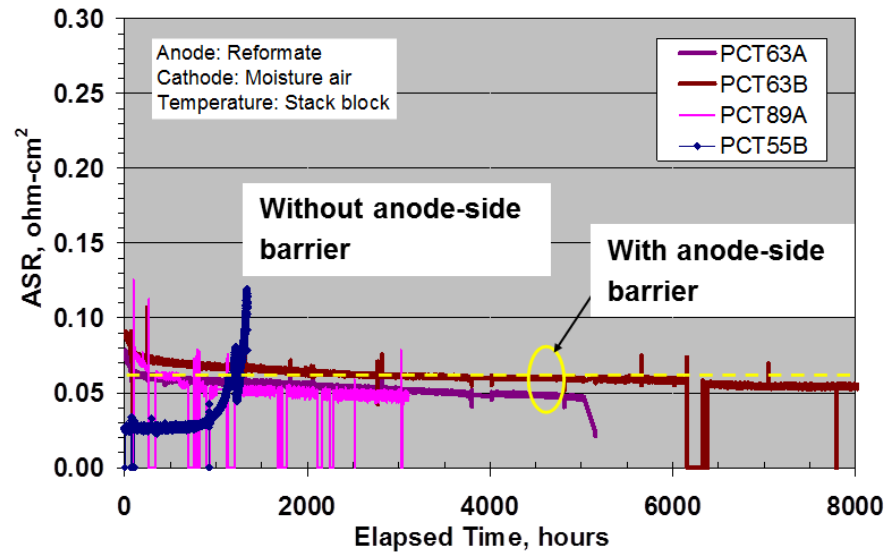
# Anode Degradation– Status of Understanding, Solutions

- Bilayer anode+ACC versus single layer
  - Avoidance of interfaces resistance
- Ni accumulation along interface at high temp and higher Uf
- Loss of TPB
- Anode-side conductivity retention important for durability
- Mn penetration through Electrolyte was not observed thus far (16000hrs)

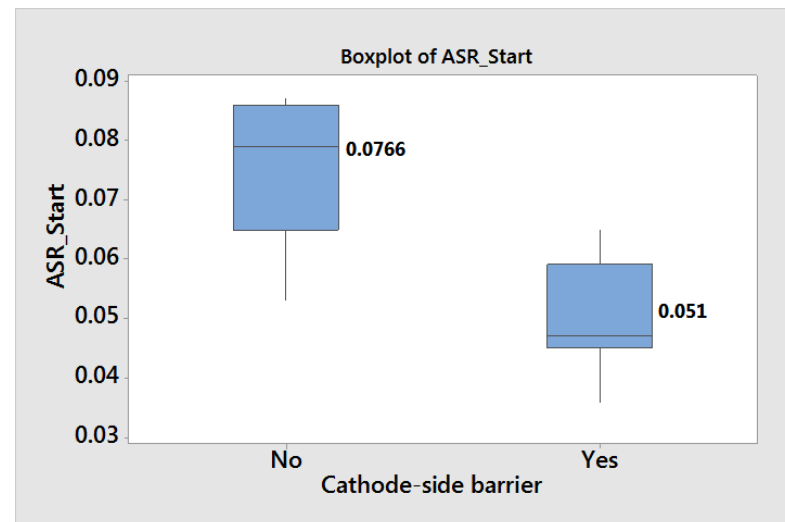


# Primary Interconnect Degradation– Status of Understanding, Solutions

- Anode-side barrier layers were applied to primary interconnect region to improve durability

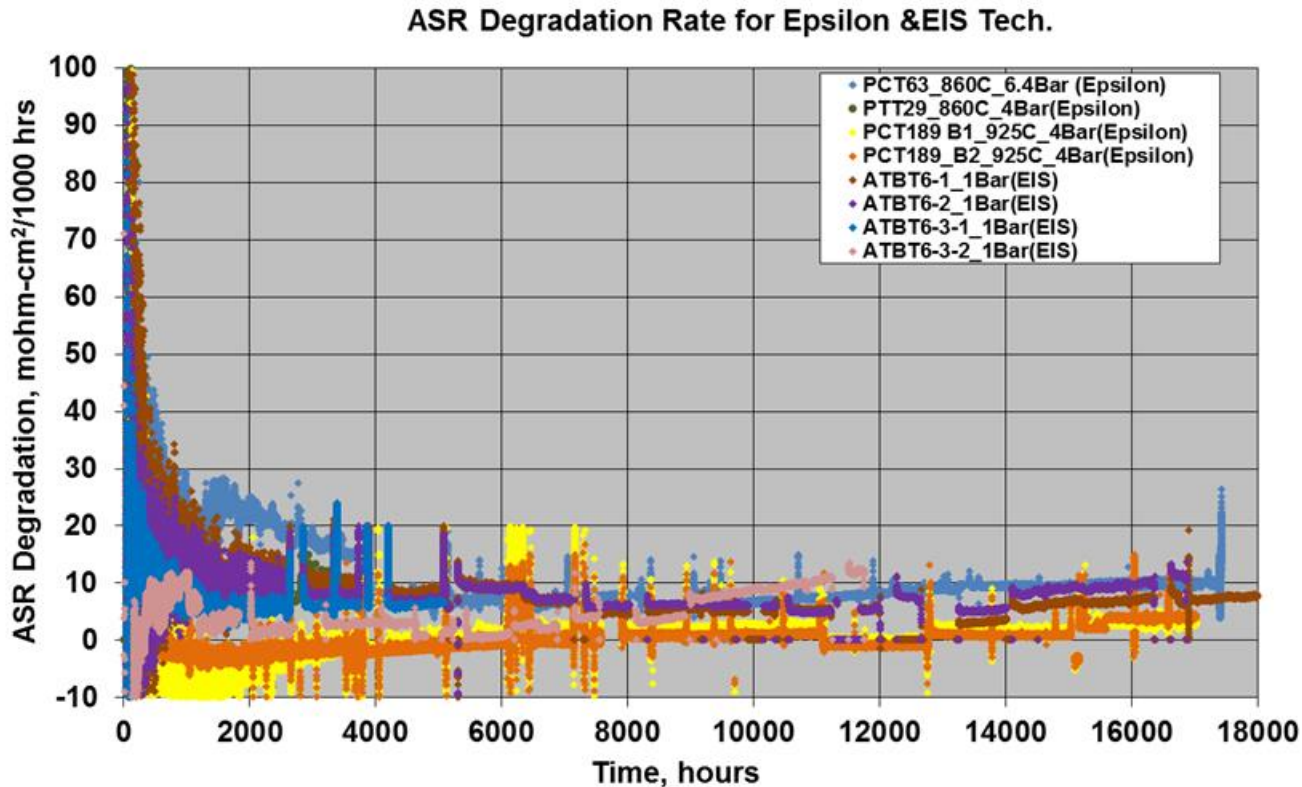


- Cathode side barrier layers further improving interface quality
  - Lower initial ASR
  - Improved long term durability



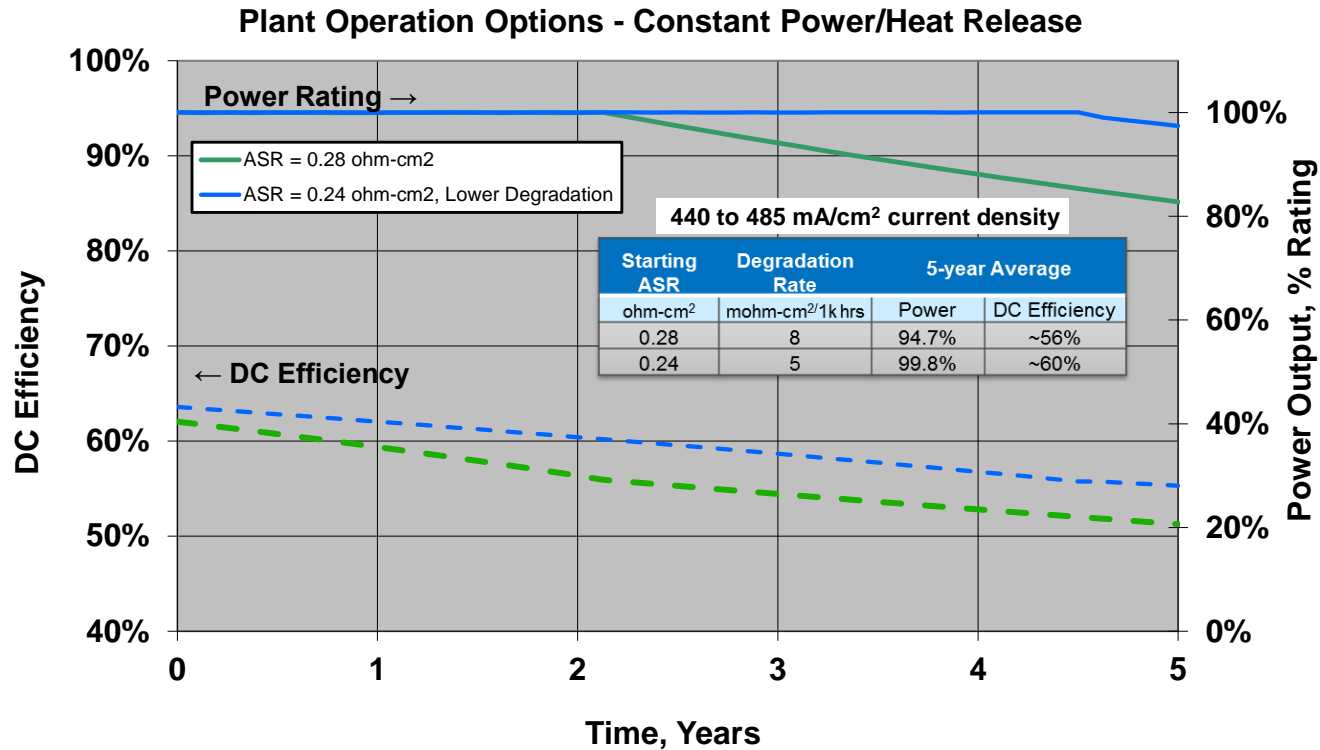
# Durability Trends: 3-10 mohm-cm<sup>2</sup>/1000 hrs

- New cathode bundle test (ATBT6) at 1 bar demonstrated < 7 mohm-cm<sup>2</sup>/1k hrs over 2 year test
- Subscale cells (PCT189) demonstrated < 3mohm-cm<sup>2</sup>/1k hrs over 2 year test
  - Correspond to 0.10~0.15%/1000hr power degradation rate



# Plant Life Improved with Lower ASR and Degradation Rate 29

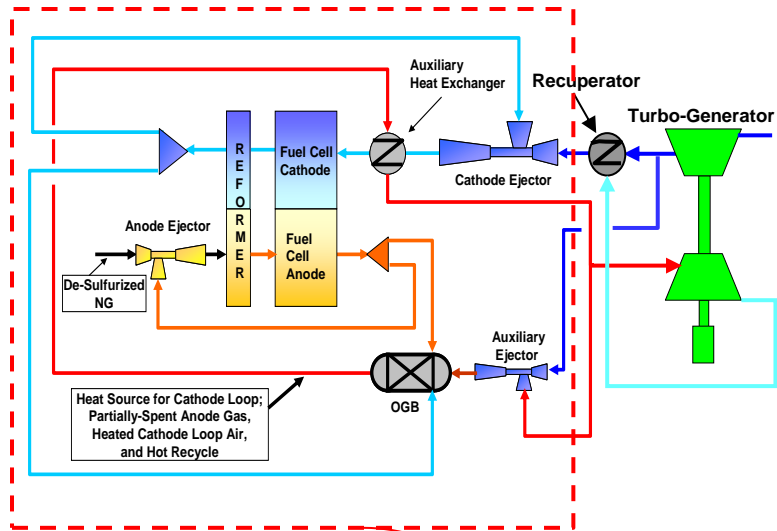
- Reduction of degradation rate from 8 to 5 mohm-cm<sup>2</sup>/1k hrs with ASR of 0.24 ohm-cm<sup>2</sup> permits nearly constant power operation over 5 year life
  - ASR reduction using lower cathode Rp + Shorter PIC + thin wall substrates > 0.04 Ohm cm<sup>2</sup>
- Average efficiency also significantly higher



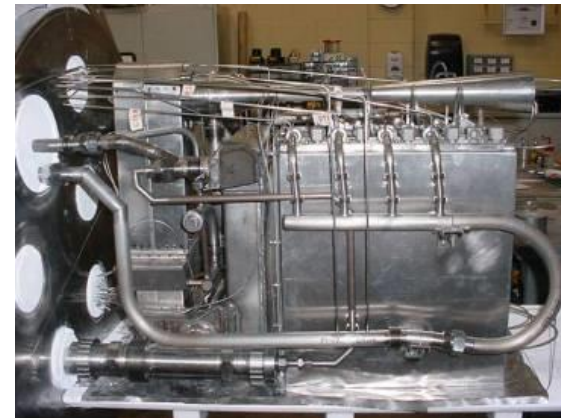
# Outline

- Performance improvement
- Cost reduction
- Durability
- **Block Testing**
  - **Block Test T1418 & T1315**
  - **IBR Block Test T1506**
- Advanced Materials and Manufacturing
- LGFCS Program

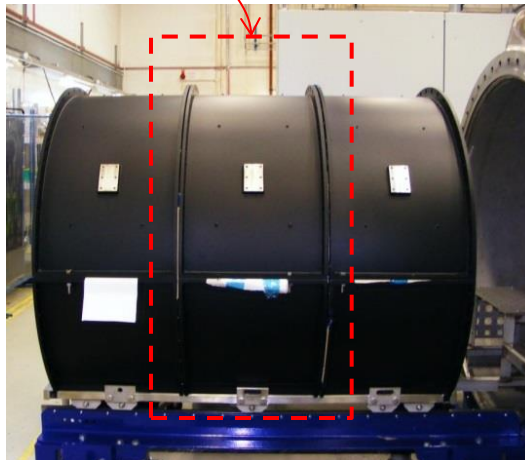
# Block Testing Matching Product Cycle, Components and Operating Conditions



Initial design of block testing rigs  
 Representative of cycle and components  
 Not packaged for product (T13xx, T14xx)



Integrated block  
 Design for product  
 (T1506)



## Test Identification

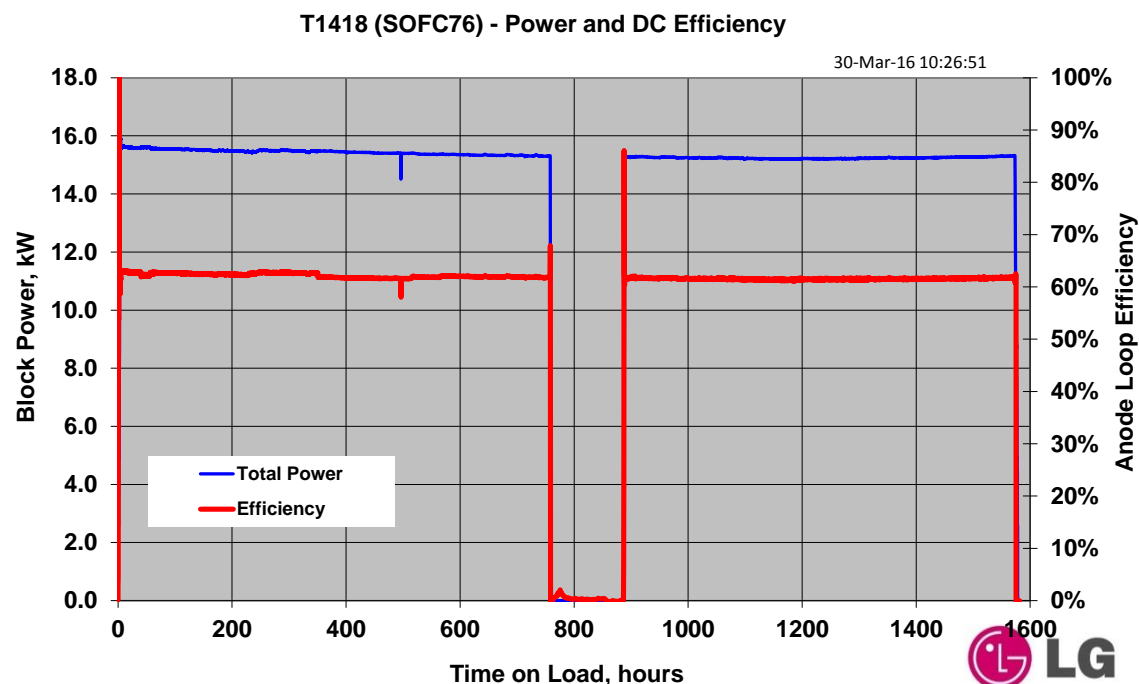
- Strip 1 – EIS1 cathode & lower ASR interconnect
- Strips 2-4 IST (Epsilon) standard strips

## Test Objectives

- Test 5000 hours with power degradation < 0.75%/1000 hrs

## Results

- 1.30% Power Degradation/1khrs
  - 0.30 ohm-cm<sup>2</sup> ASR at 1500 hours was as expected
- Average DC Efficiency ~ 62%
- Completed 1450 hours on load
  - Test run short due to BOP issues
  - Decision to convert rig to IB standard





## Test Identification

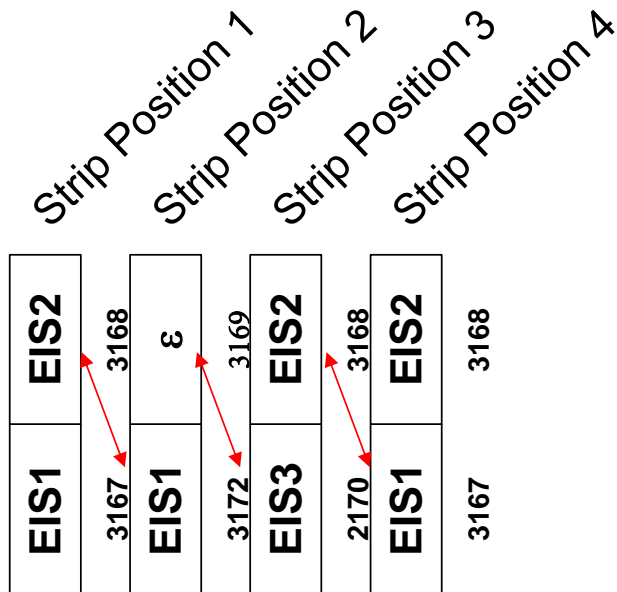
- 4 different cathode configurations
  - Standard IST (epsilon)
  - 3 EIS candidates
- Lower ASR interconnect
- IST (Epsilon) standard anode

## Test Objective

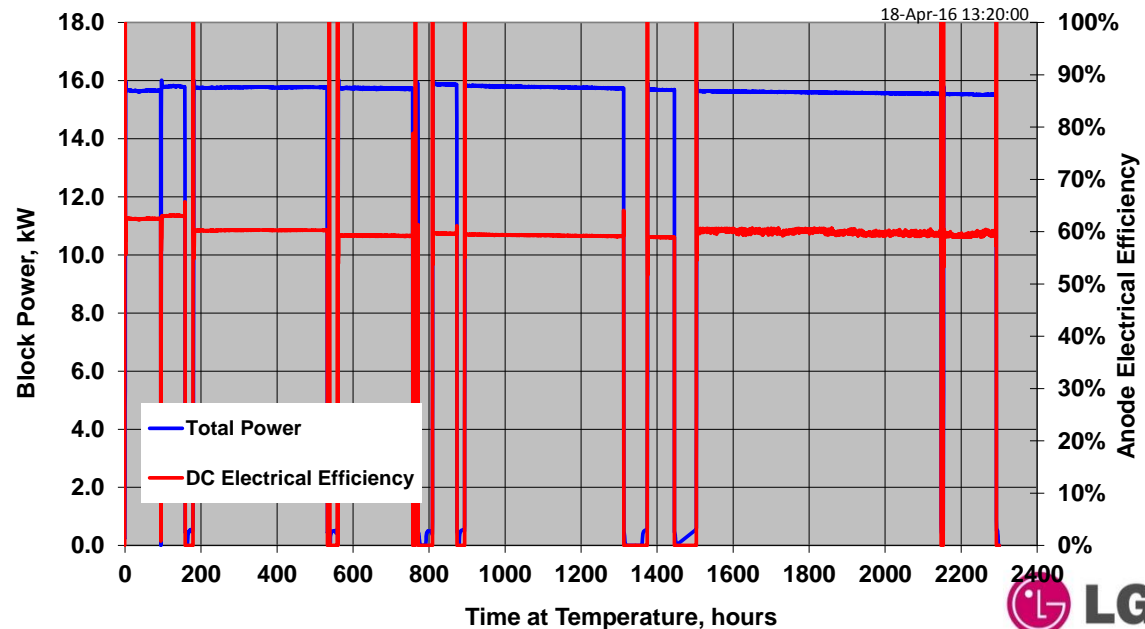
- Test 2000 hours with power degradation < 1.5%/1000 hrs

## Results

- 0.78% Power Degradation/1khrs
- Average DC Efficiency ~ 60%
- Completed 2049 hours on load

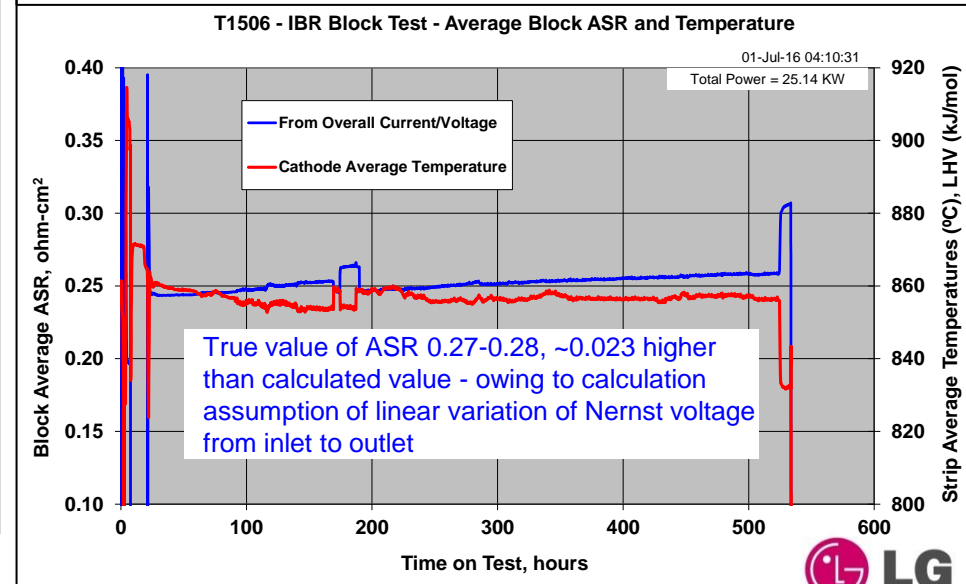
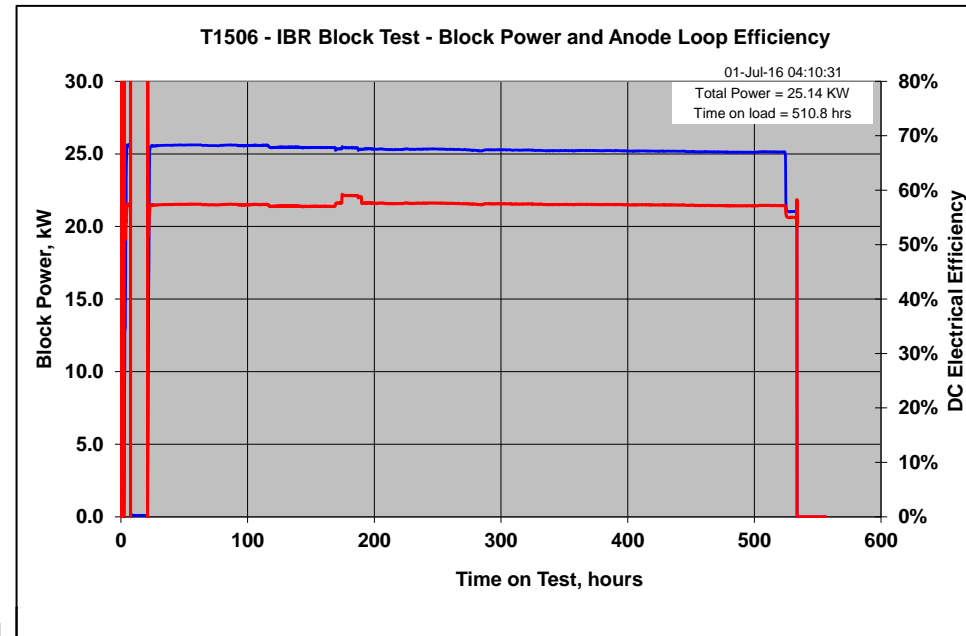


T1315 (Block 3 in SOFC73) - Block Power

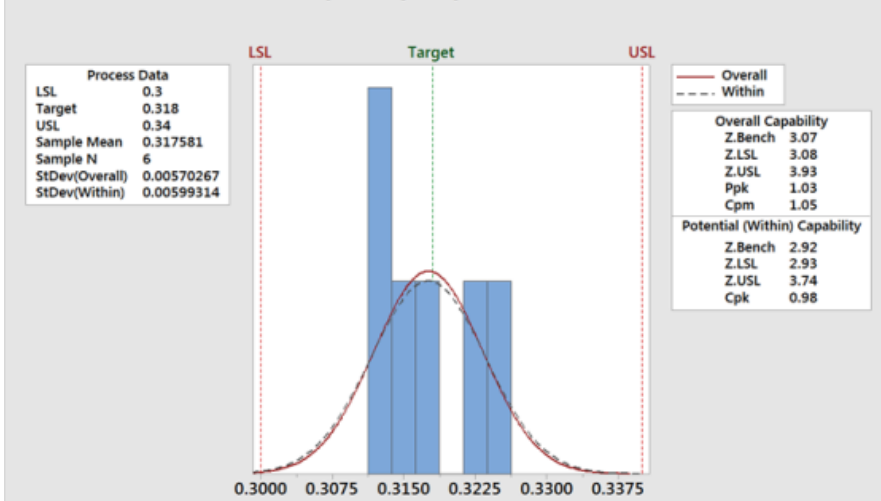


# T1506: Demonstration of In-Block Reforming

- Initial power 25.6 kW
  - Highest single block power
- Test duration 511 hours on load
- Lowest block ASR tested
- Achieved  $<80^{\circ}\text{C}$  dT
- Strip Technology
  - EIS1 Cathode
  - Lower ASR interconnect

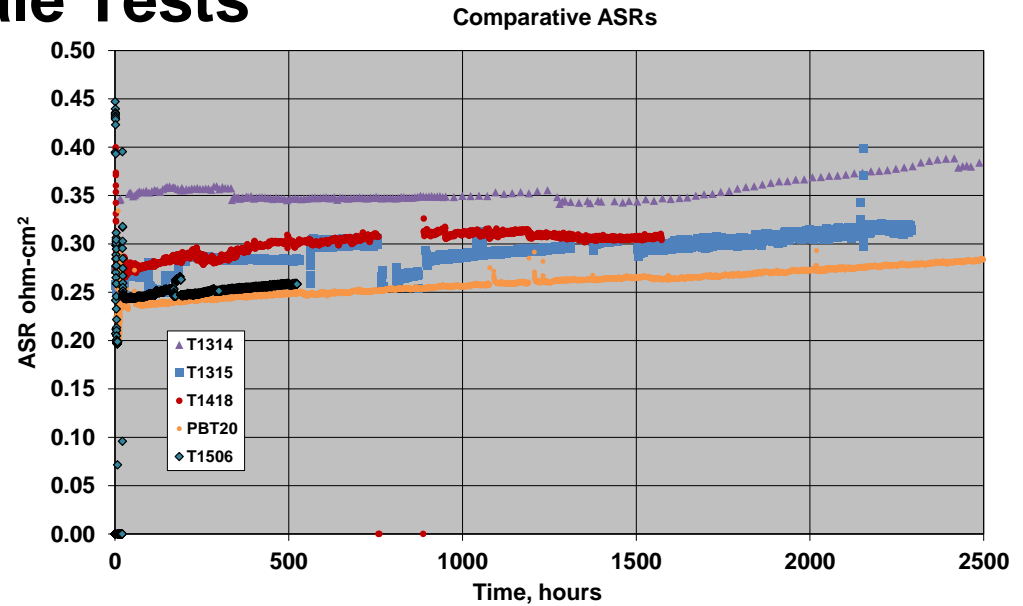


Process Capability Report for ASR at 860C

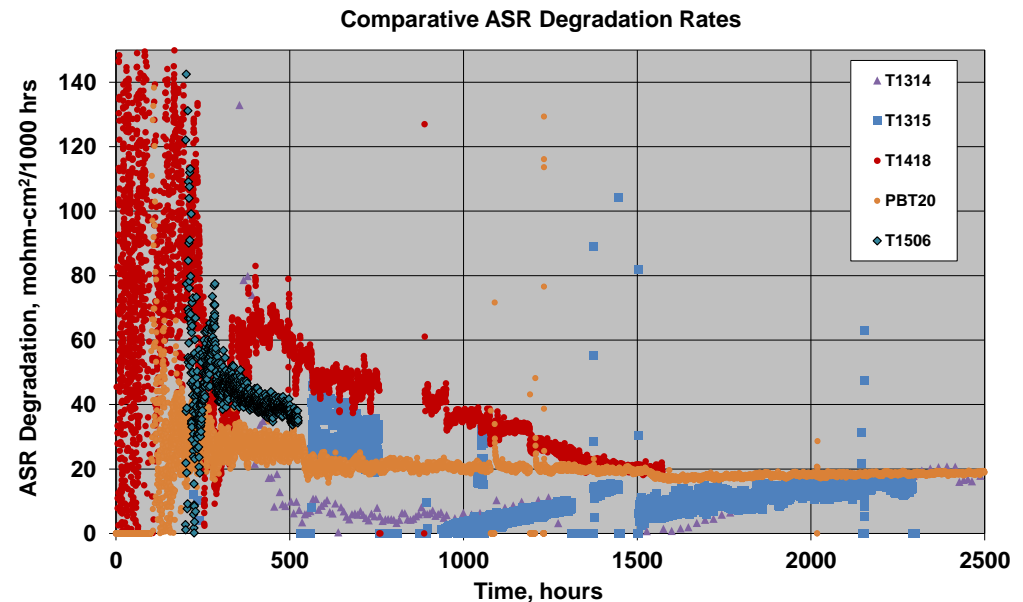


# IBR Block Performance: Within Range of Sub-scale Tests

- Improved block ASR from T1314 to T1315/T1418
- Excellent correlation from bundle PBT20 to block T1506



- ASR degradation rates tend to converge after longer test periods



# Block Performance Summary

Parameter	T1314	T1418	T1315	T1506
Initial Power (Normalized for 5 strips)	18.8 kW	19.5 kW	19.7 kW	25.6 kW
Starting ASR (ohm-cm <sup>2</sup> )	0.35	0.28	0.28	0.27 <sup>Note 1</sup>
Current Density (mA/cm <sup>2</sup> )	380	380	380	530
Fuel (@ 75 – 80% U <sub>f</sub> )	Bottled CH <sub>4</sub>	PNG	Bottled CH <sub>4</sub>	PNG
Power Degradation (per 1000hrs)	1.2%	1.3%	0.78%	Note 2
Duration (hours)	3040	1450	2049	520 <sup>Note 3</sup>
Cell Technology	Pre-Eps	Eps, EIS	EIS	EIS + IBR

Note 1: Accounting for non-linear Nernst voltage

Note 2: Power Degradation rate given once test accumulates >1000hrs of test time

Note 3: Still under test

# Outline

- Performance improvement
- Cost reduction
- Durability
- Block Testing
- **Advanced Materials and Manufacturing**
  - **Task 2.0**
  - **Task 3.0**
- LGFCS Program

# Advanced Materials and Manufacturing

- **Task 2.0: Identify Candidate Components**
  - Cathode and Anode Ejectors
  - Cathode and Anode Pipework
- **Task 3.1: Identify Materials**
  - Anode Ejector (low temp.) - continue using SS 310/316
  - Auxiliary Ejector (high temperature) materials considered
    - H120, RA330, AFA25, 601, and 230
- **Task 3.2 Identify Processes**

• additive manufacturing (AM)	• spin forming
• metal injection molding (MIM)	• lost wax casting
• hot isostatic pressing (HIP)	• other processes

# Advanced Materials Project Status Summary

- **Key Findings**

- **Five candidate alloys identified based on material requirements**
- **Preliminary cost study suggests ~50% reduction for aux. ejector**
- **Metal Injection Molded (MIM) coupling fitting cost ~\$8 & \$9 at 50 MW quantities**
  - **Estimated 77% - 89% cost reduction vs low-volume machined component**

- **Lessons Learned**

- **Additive Manufacturing Process is only cost effective for the complex nozzle assembly**
- **Other manufacturing processes are being explored**
  - **spin forming**
  - **lost wax casting**

# Summary

- **Significant progress made regarding performance improvements and durability. There is a better understanding on how to increase the life of the LGFCS fuel cell. These improvements will have a direct impact on reducing costs.**
- **Block testing, though challenging, has shown that ASR tracks across multiple scales. Improvements in cell technology and system performance allowed for LGFCS's best block test to date.**
- **The advanced materials and manufacturing project continues to support material selection and cost reduction of critical components.**



# Acknowledgements

- **Special thanks to LGFCS project managers Patcharin Burke, Shailesh Vora, and the entire SOFC program management team**
- **This material is based upon work supported by the U.S. Department of Energy, National Energy Technology Laboratory under Award Number DE-FE0012077, DE-FE0023337, and DE-FE0026098**
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